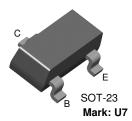


BSR13

NPN General Purpose Amplifier

• Sourced from process 10.



Absolute Maximum Ratings* T_a =25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{CEO}	Collector-Emitter Voltage	30	V
V _{CBO}	Collector-Base Voltage	60	V
V _{EBO}	Emitter-Base Voltage	5.0	V
I _C	Collector Current - Continuous	0.5	А
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 ~ 150	°C

^{*} This ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

These rating are based on a maximum junction temperature of 150 degrees C.
 These are steady limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Electrical Characteristics T_a=25°C unless otherwise noted

Symbol	Parameter	Test Condition	Min.	Max.	Units
Off Charac	cteristics			•	•
V _{(BR)CEO}	Collector-Emitter Breakdown Voltage *	$I_C = 10 \text{mA}, I_B = 0$	30		V
V _{(BR)CBO}	Collector-Base Breakdown Voltage	$I_C = 10\mu A, I_E = 0$	60		V
V _{(BR)EBO}	Emitter-Base Breakdown Voltage	$I_E = 10\mu A, I_C = 0$	5.0		V
I _{CBO}	Collector Cutoff Current	$V_{CB} = 50V, I_{E} = 0$ $V_{CB} = 50V, I_{E} = 0, T_{a} = 150^{\circ}C$		30 10	nA μA
I _{EBO}	Emitter Cutoff Current	$V_{EB} = 3.0V, I_{C} = 0$		15	nA
On Charac	cteristics			•	•
h _{FE}	DC Current Gain	$\begin{split} I_C &= 0.1 \text{mA}, \ V_{CE} = 10 \text{V} \\ I_C &= 1.0 \text{mA}, \ V_{CE} = 10 \text{V} \\ I_C &= 10 \text{mA}, \ V_{CE} = 10 \text{V} \\ I_C &= 150 \text{mA}, \ V_{CE} = 10 \text{V} \\ I_C &= 150 \text{mA}, \ V_{CE} = 1.0 \text{V} \\ I_C &= 500 \text{mA}, \ V_{CE} = 10 \text{V} \\ \end{split}$	35 50 75 100 50 30	300	
V _{CE(sat)}	Collector-Emitter Saturation Voltage *	I _C = 150mA, I _B = 15V I _C = 500mA, I _B = 50V		0.4 1.6	V
V _{BE(sat)}	Base-Emitter Saturation Voltage	I _C = 150mA, I _B = 15V I _C = 500mA, I _B = 50V		1.3 2.6	V
Small Sign	nal Characteristics				
fт	Curent Gain Bandwidth Product	$I_C = 20 \text{mA}, V_{CF} = 20 \text{V}, f = 100 \text{MHz}$	250		

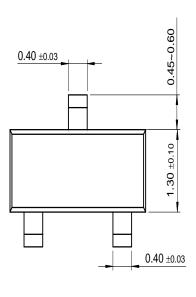
* Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2.0%

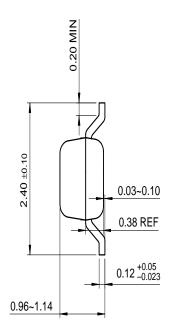
Thermal Characteristics T _a =25°C unless otherwise noted			
Symbol	Parameter	Max.	Units
P_D	Total Device Dissipation Derate above 25°C	350 2.8	mW mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	357	°C/W

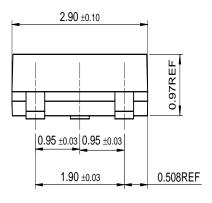
^{*} Device mounted on FR-4PCB 1.6" × 1.6" × 0.06".

Package Dimensions

SOT-23







Dimensions in Millimeters

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